

Fig. 3

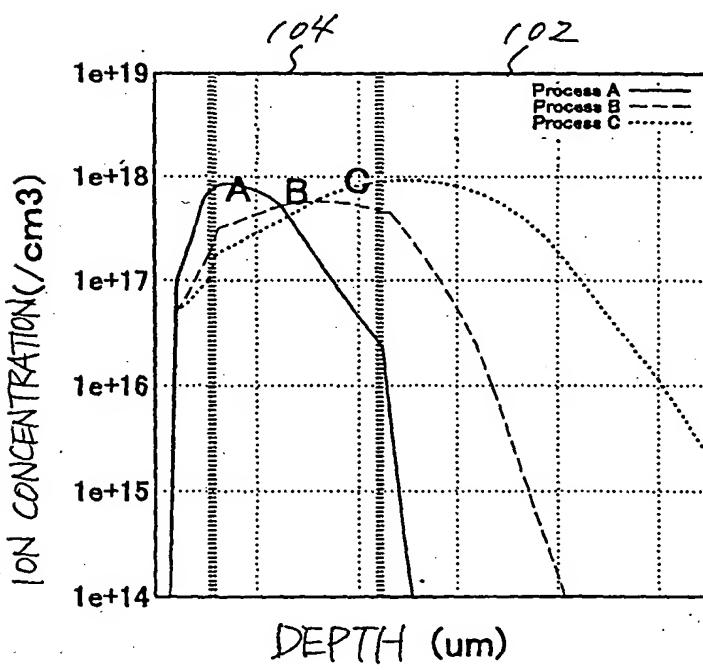


Fig. 4

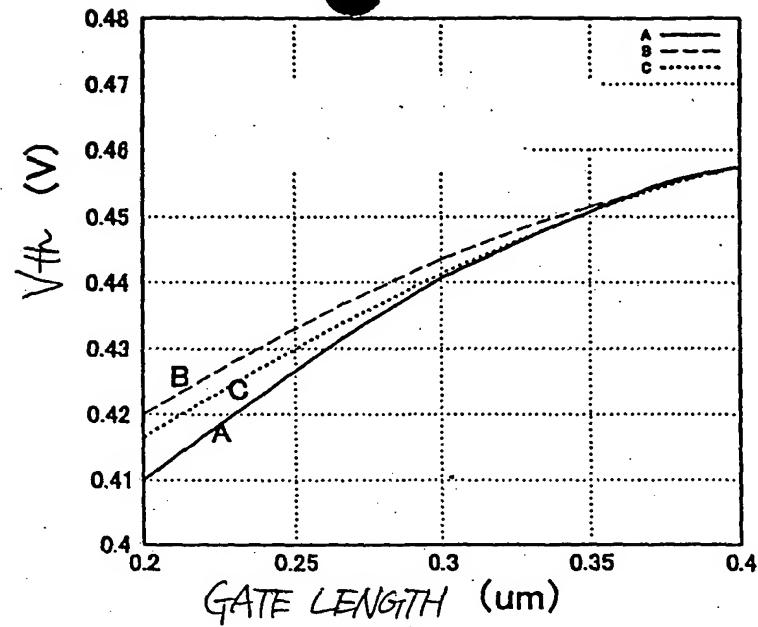


Fig-5

Fig. 6(a)

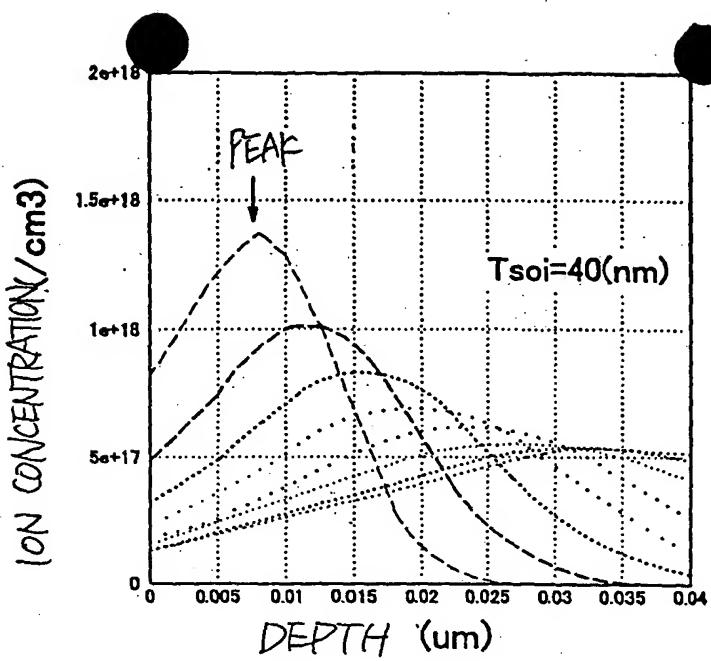
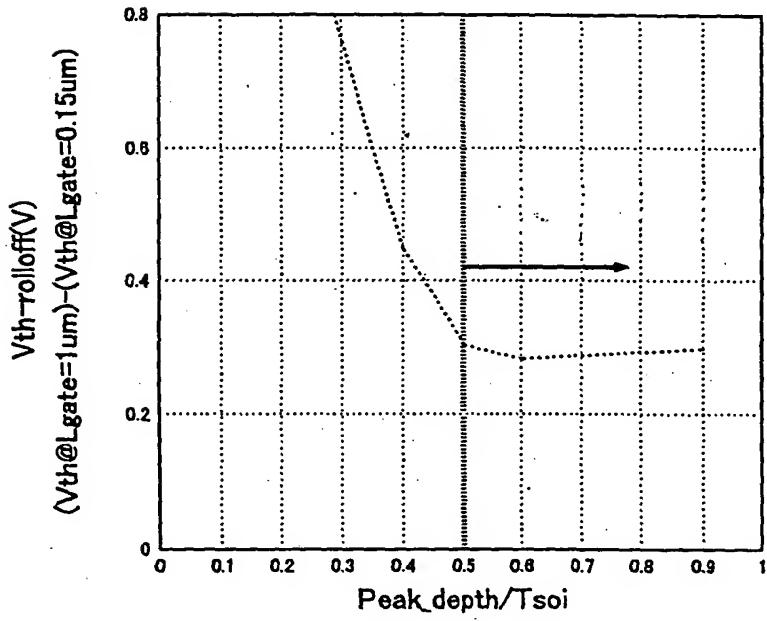


Fig. 6(b)



20252025202520252025202520252025

Fig.7(a) Y[um]

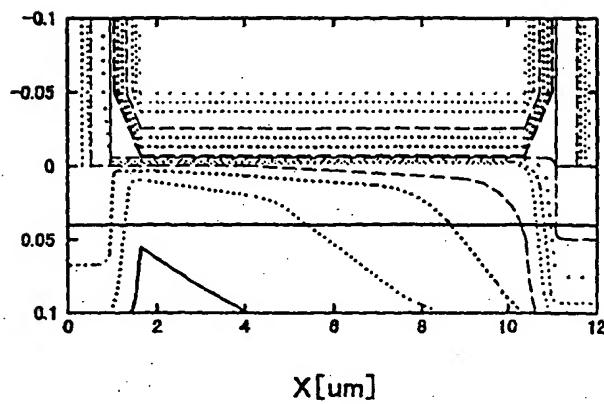
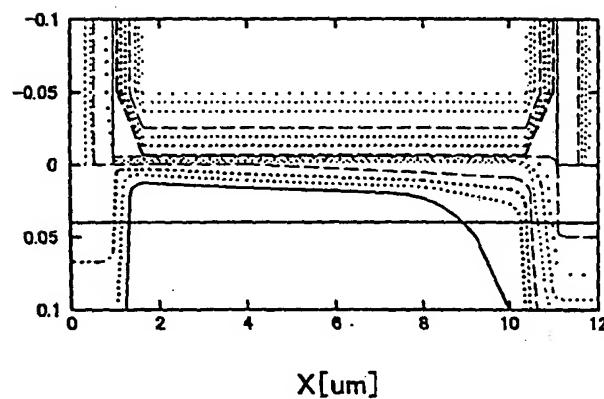
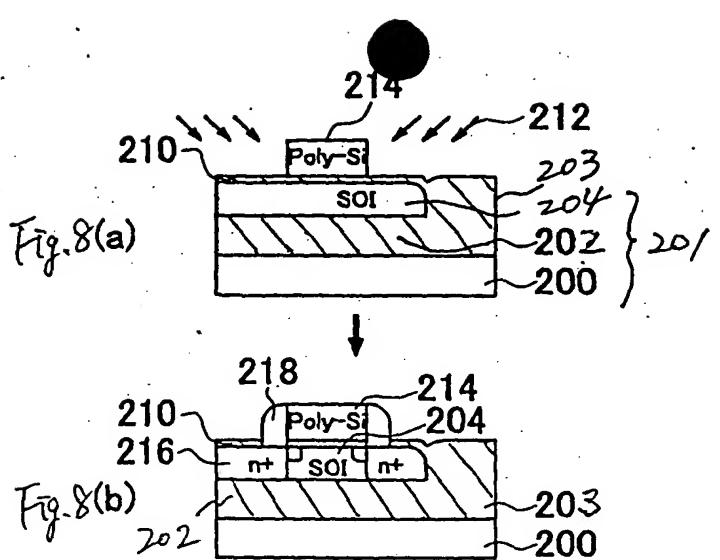
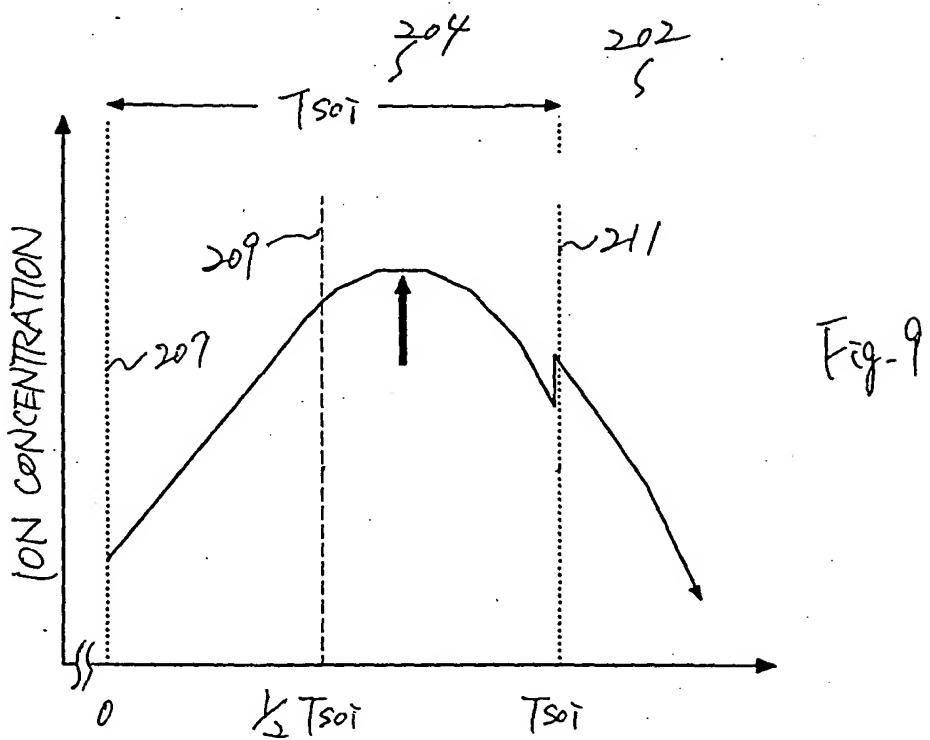


Fig.7(b) Y[um]





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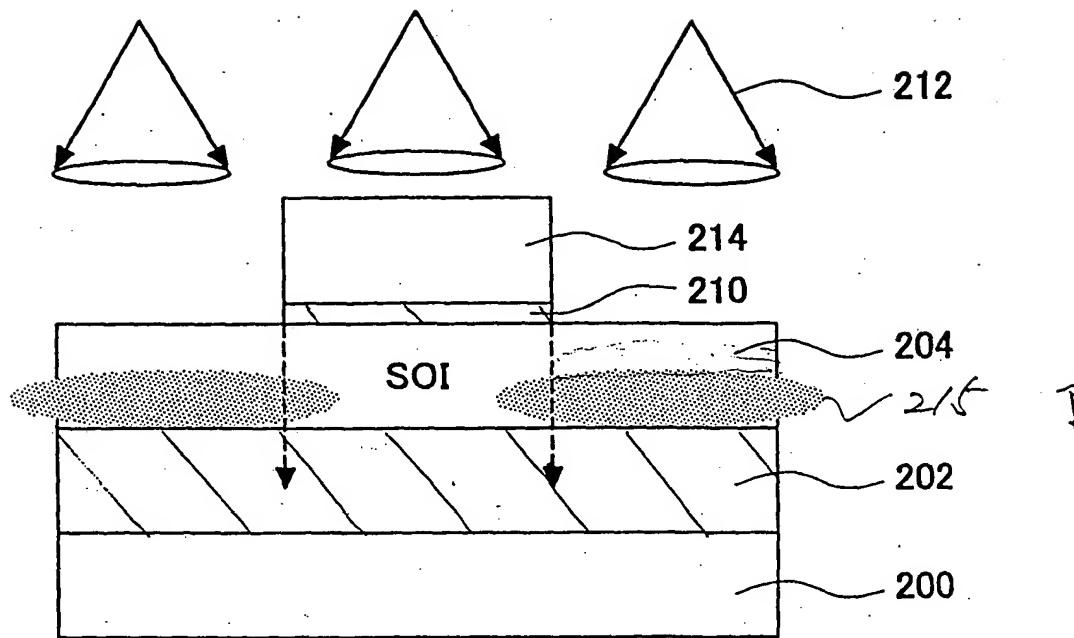


Fig-10

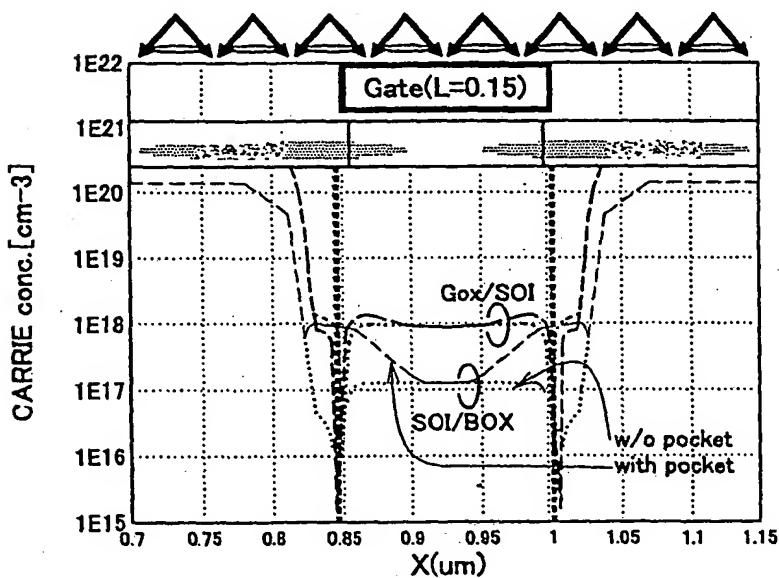


Fig-11

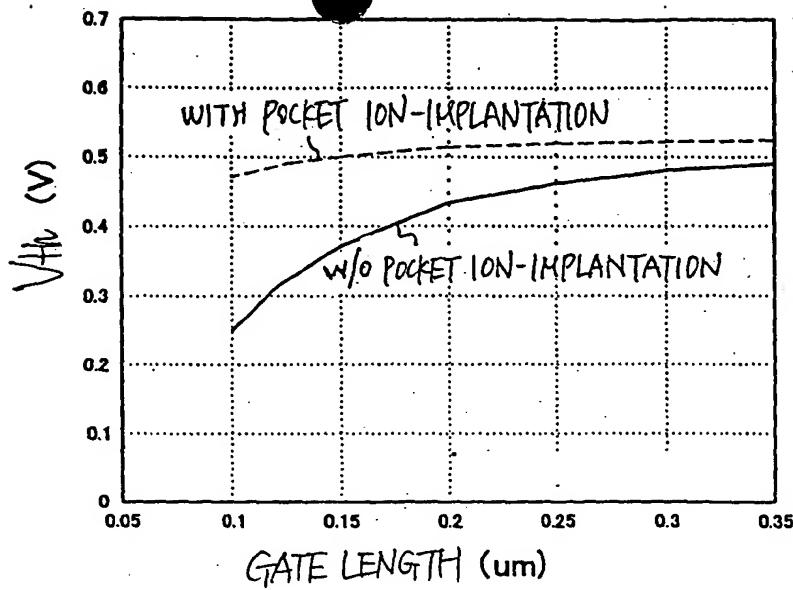
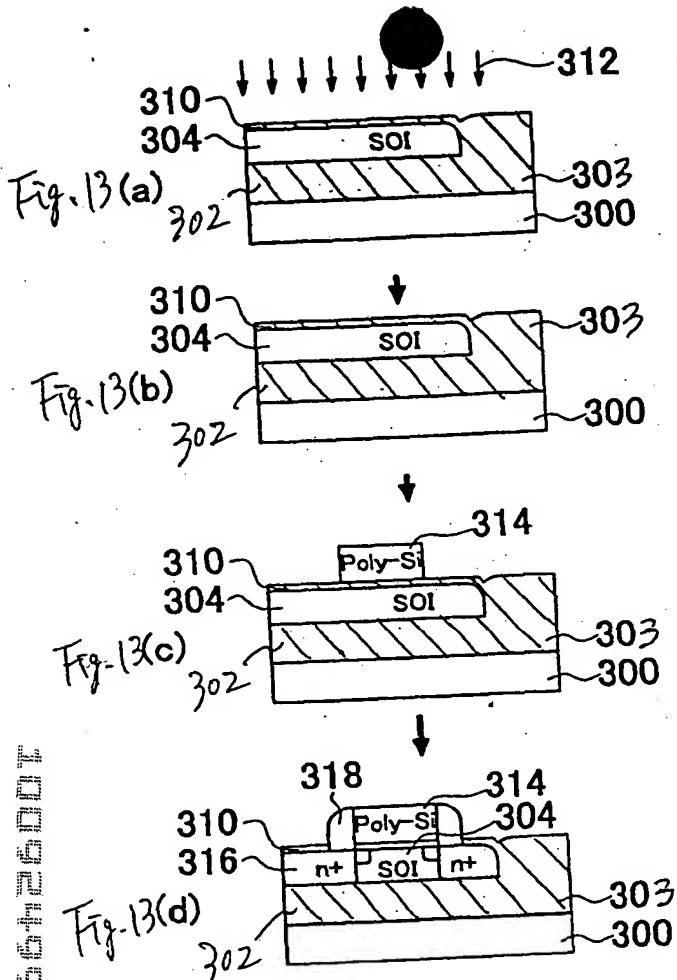


Fig-12



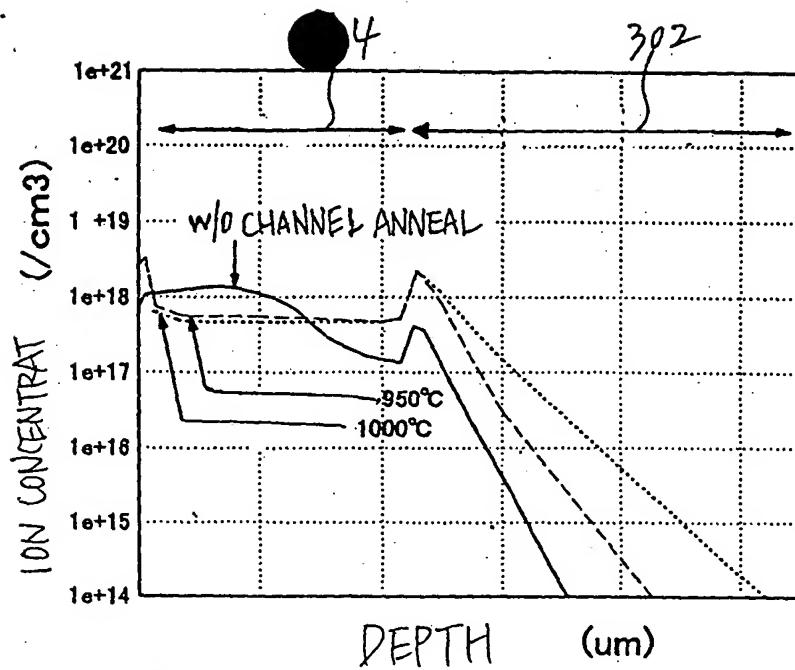


Fig. 14

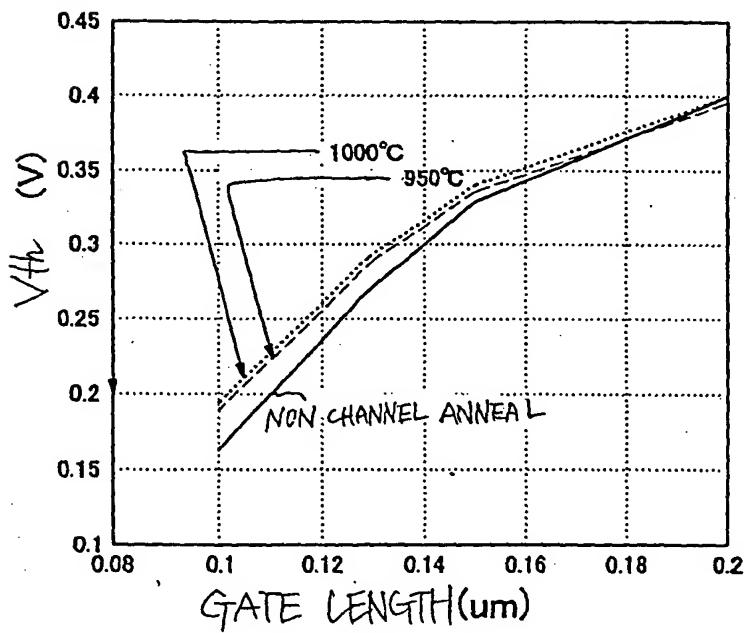
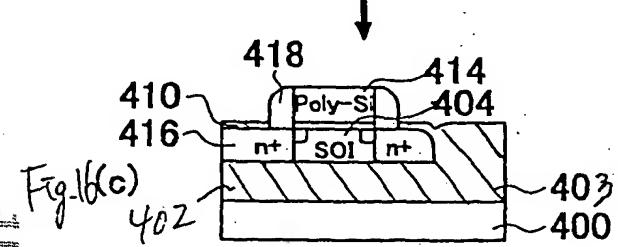
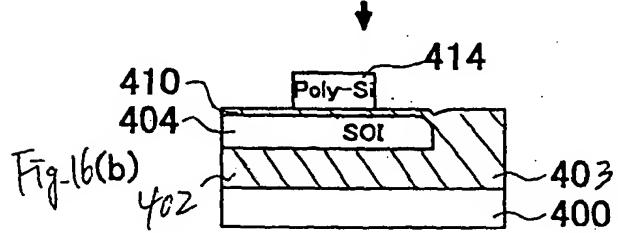
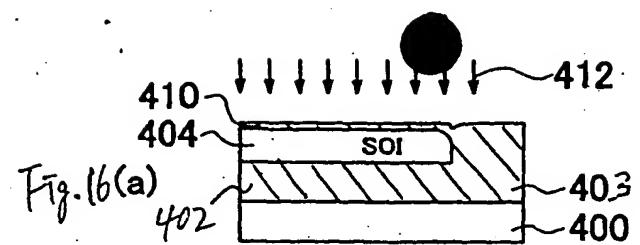


Fig. 15



PROBLEMS IN FABRICATION

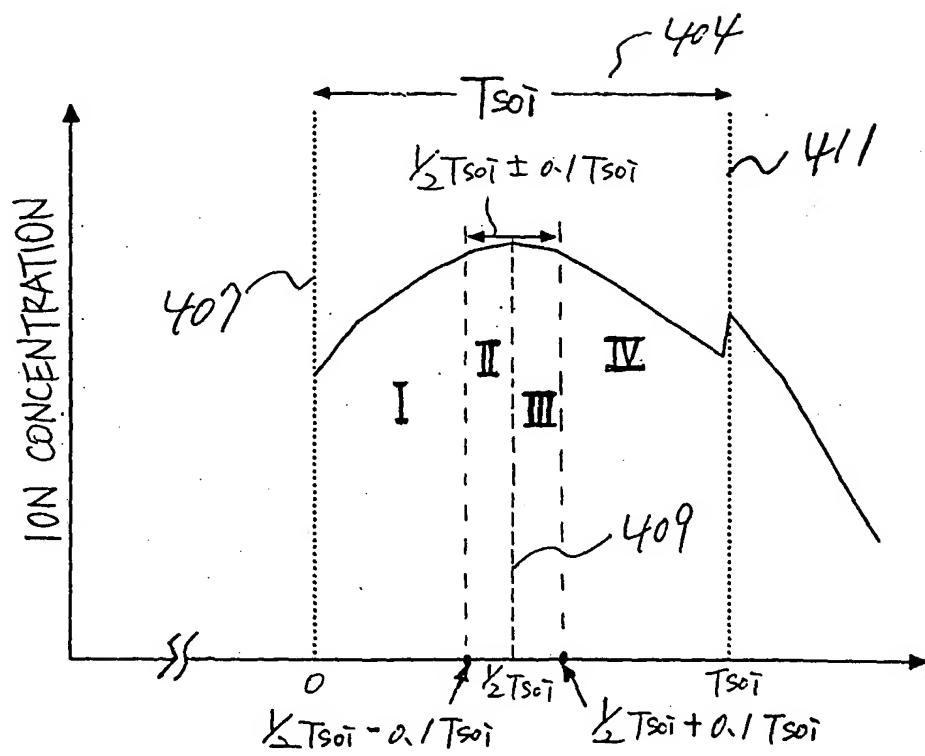


Fig. 18(a)

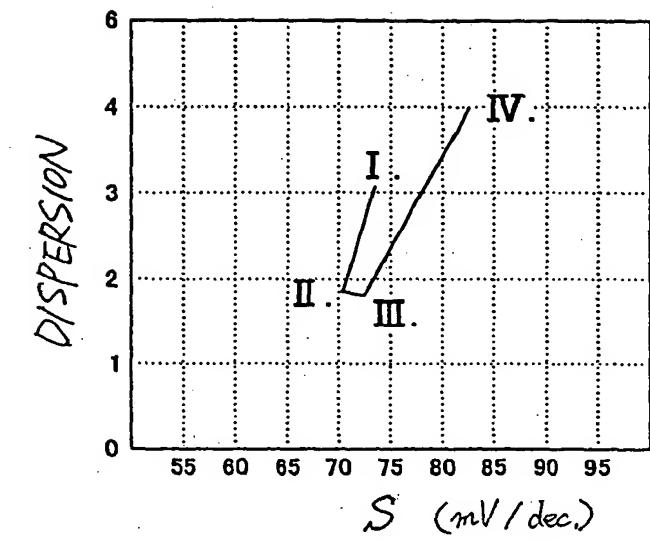
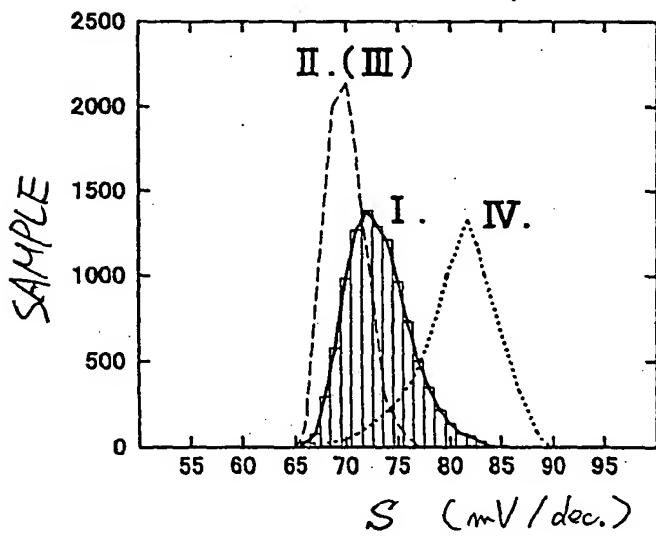
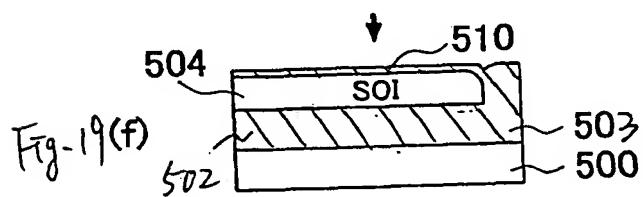
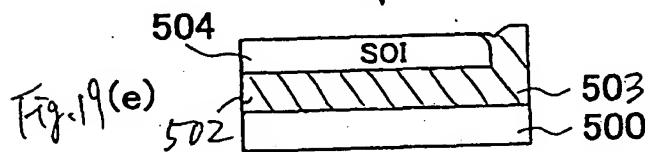
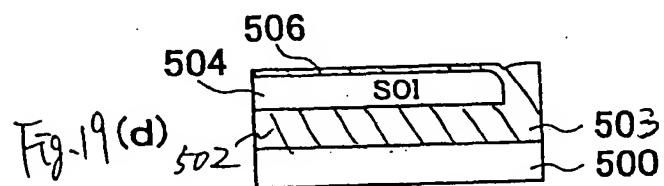
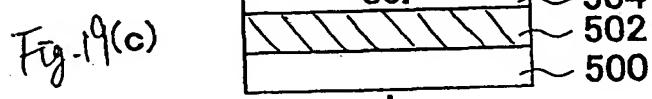
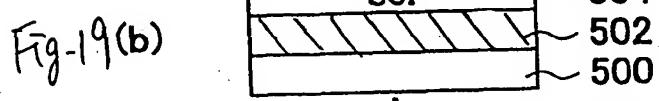
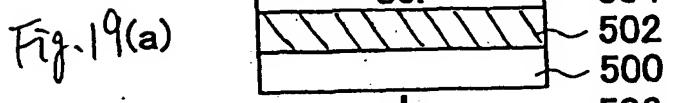
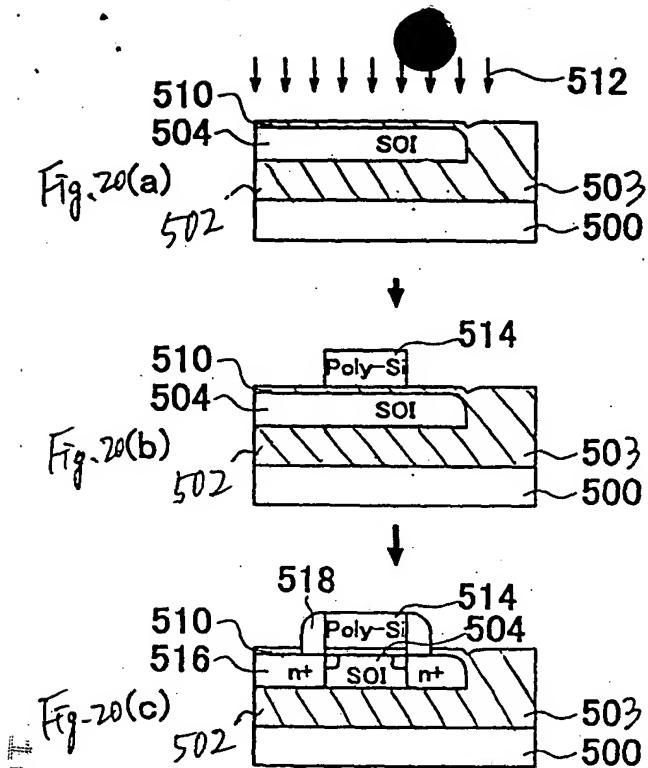


Fig. 18(b)







TOP-GATE FET WITH SOI

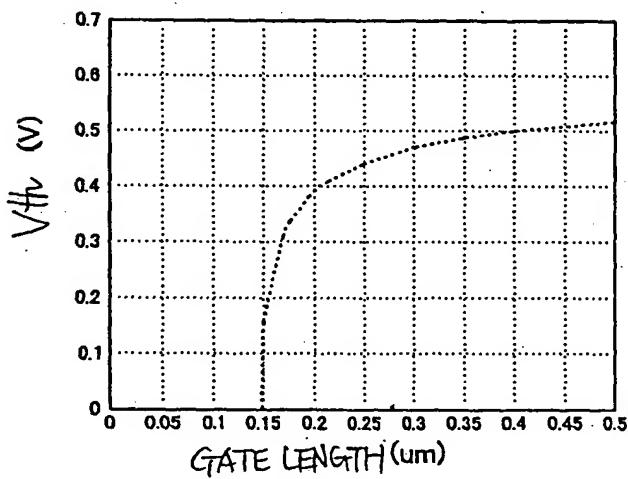


Fig. 21

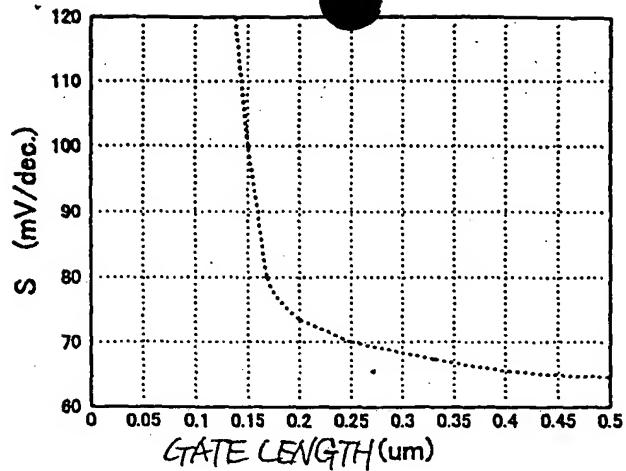


Fig. 22

PROBLEMS & EXERCISES

23(a)

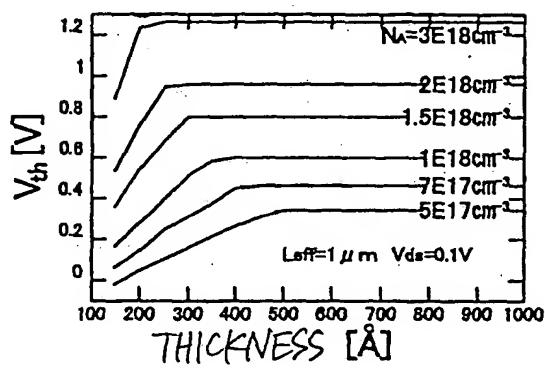


Fig. 23(b)

